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L1	9018	personal near3 identificat\$3 and (bio or biometric or fingerprint or finger adj print oe face or facial or voice adj print or signature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 09:03
L2	10	1 and transfer\$3 same portable same(storage or memory)same IC near3 card	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 09:10
L3	0	2 and transfer\$3 same portable same(storage or memory)same IC near3 card same algorithm	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 09:11
L4	0	2 and transfer\$3 same portable same(storage or memory)same IC near3 card same algorithm same notify\$3 near3 terminal same (accept\$3 or reject\$3 or flaw or fault)same identificat\$3 near2 result	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 09:13

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Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
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Example: optical <and> (fiber <or> fibre) <in> ti

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